22 nm SRAM Announcement

Mark Bohr Intel Senior Fellow Logic Technology Development



Sept 2009

22 nm Shuttle Test Chip

SRAM, Logic, Mixed-Signal Test Circuits

SRAM, Logic, Mixed-Signal Test Circuits

> Discrete Test Structures



Intel is first in the industry to demonstrate working 22 nm circuits



22 nm SRAM Test Chip

- 364 Mbit array size
- >2.9 billion transistors
- 3rd generation high-k + metal gate transistors
- Same transistor and interconnect features as on 22 nm CPUs



Demonstrating working 22 nm SRAMs is an important milestone towards building working 22 nm microprocessors



22 nm SRAM Test Chip



0.092 um² SRAM cell for high density applications



0.108 um² SRAM cell for low voltage applications



0.092 um² is the smallest SRAM cell in working circuits reported to date



22 nm SRAM Test Chip



Test chip includes logic and mixed-signal circuits to be used on 22 nm microprocessors



Intel Logic Technology Roadmap



Intel is now developing both CPU and SoC versions of each technology generation



THANK YOU



Sept 2009